

Application No.	Applicant(s)	~
10/773,208	SHIN ET AL.	
Examiner	Art Unit	
Antonio A Caschera	2676	

SEARCHED				
Class	Subclass	Date	Examiner	
345	590, 591, 604	3/1/05	AC	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Keyword Searched: 345/589, 601 382/167	2/25/05 & 3/1-2/05	AC
Searched NPL: IEEE & ACM Digital Libraries	3/2/05	AC
Searched Euro and Japanese Patent Websites	3/2/05	AC .
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